

# United States Patent [19]

## **Erskine**

**Patent Number:** [11]

5,642,194

[45] Date of Patent: Jun. 24, 1997

## [54] WHITE LIGHT VELOCITY INTERFEROMETER

[75] Inventor: David J. Erskine, Oakland, Calif.

[73] Assignee: The Regents of the University of

California, Oakland, Calif.

[21] Appl. No.: 597,082

[22] Filed: Feb. 5, 1996

356/358

356/358, 349

### [56] References Cited

### U.S. PATENT DOCUMENTS

4,915,499	4/1990	Gidon et al	356/28.5
5,502,466	3/1996	Kato et al	356/28.5

### OTHER PUBLICATIONS

Gidon et al., Multiple-line laser Doppler velocimetry, Jun. 1, 1988, vol. 27, No. 11, Applied Optics.

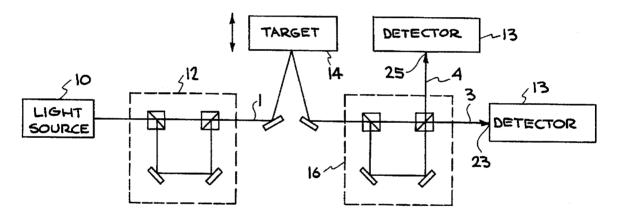
Primary Examiner—Frank Gonzalez Assistant Examiner-Robert Kim

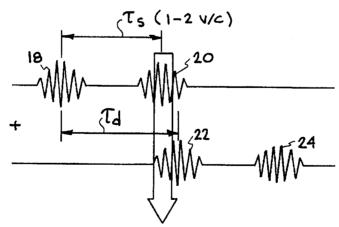
Attorney, Agent, or Firm-Henry P. Sartorio; John P. Wool-

### [57] ABSTRACT

The invention is a technique that allows the use of broadband and incoherent illumination. Although denoted white light velocimetry, this principle can be applied to any wave phenomenon. For the first time, powerful, compact or inexpensive sources can be used for remote target velocimetry. These include flash and arc lamps, light from detonations, pulsed lasers, chirped frequency lasers, and lasers operating simultaneously in several wavelengths. The technique is demonstrated with white light from an incandescent source to measure a target moving at 16 m/s.

### 24 Claims, 14 Drawing Sheets





CONSTRUCTVE OR DESTRUCTIVE INTERFERENCE